

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/529,616 | | Applicant(s)/Patent Under Reexamination BEZIAT ET AL. | |
| | Examiner Michael Maskell | | Art Unit 2809 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-4,486,512 A | 12-1984 | Tozawa et al. | 428/623 |
| * | B | US-4,508,969 A | 04-1985 | Janberg et al. | 250/506.1 |
| * | C | US-4,700,863 A | 10-1987 | Filippi et al. | 220/613 |
| * | D | US-5,391,887 A | 02-1995 | Murray, Jr., Holt | 250/506.1 |
| * | E | US-5,787,688 A | 08-1998 | Peulve et al. | 53/478 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------------|----------------|
| | N | DE 3405735 A1 | 08-1985 | Germany | BIENEK et al. | G21F 05/00 |
| | O | DE 3405735 A | 08-1985 | Germany | BIENEK et al. | B23K 23/00 |
| | P | JP 09262658 A | 10-1997 | Japan | HIRAMATSU et al. | B22D 19/04 |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.